

### **Description**

The DMC3025LNS uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a

Battery protection or in other Switching application.

### **General Features**

V<sub>DS</sub> = 30V I<sub>D</sub> =16 A

 $R_{DS(ON)}$  < 20m $\Omega$  @  $V_{GS}$ =10V

 $V_{DS} = -30V I_{D} = -14A$ 

 $R_{DS(ON)} < 30 m\Omega$  @  $V_{GS}=10V$ 

# **Application**

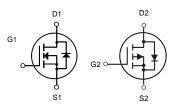
**Battery protection** 

Load switch

Uninterruptible power supply

#### S2 G1 D2 D2 D2 D1 D1 D1 Pin 1

DFN3X3-8L



N-Channel

P-Channel

### **Package Marking and Ordering Information**

Product ID	Pack	Brand	Qty(PCS)
DMC3025LNS	DFN3X3-8L	HXY MOSFET	5000

### Absolute Maximum Ratings (T<sub>C</sub>=25<sup>°</sup>Cunless otherwise noted)

		Rating		
Symbol	Parameter	N-Channel	P-Channel	Units
Vos	Drain-Source Voltage	30	-30	V
V <sub>G</sub> s	Gate-Source Voltage	±20	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	16	-14	А
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	5	-4	А
Іом	Pulsed Drain Current <sup>2</sup>	40	-40	Α
EAS	Single Pulse Avalanche Energy <sup>3</sup>	26.6	110	mJ
las	Avalanche Current	8.7	- 20	Α
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	10.8	10.8	W
P <sub>D</sub> @T <sub>A</sub> =100°C	Total Power Dissipation <sup>4</sup>	2	2	W
Тѕтс	Storage Temperature Range	-55 to 150	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C
R <sub>0</sub> JA	Thermal Resistance Junction-Ambient <sup>1</sup>		62	°C/W
Rejc	Thermal Resistance Junction-Case <sup>1</sup>		6	°C/W



# N-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30			V
$\triangle BV_{DSS}/\!\triangle T$	BVDSS Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.023		V/°C
В	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =10A		14	20	mΩ
R <sub>DS(ON)</sub>	Static Dialii-Source On-Resistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =6A		20	25	1115.2
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> . I <sub>D</sub> =250uA	1.0		2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> -V <sub>DS</sub> , I <sub>D</sub> -250uA		-4.2		mV/°C
	Drain Source Leekage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =10A		14		S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		2.3		Ω
Qg	Total Gate Charge (4.5V)			5		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =20V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =10A		1.11		nC
Q <sub>gd</sub>	Gate-Drain Charge			2.61		
T <sub>d(on)</sub>	Turn-On Delay Time			7.7		
Tr	Rise Time	$V_{DD}$ =12V , $V_{GS}$ =10V , $R_{G}$ =3.3 $\Omega$		46		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =6A		11		ns
T <sub>f</sub>	Fall Time			3.6		
C <sub>iss</sub>	Input Capacitance			416		
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		62		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			51		
Is	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			16	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,5</sup>	vg-vp-ov , roice Cuitefit			30	Α
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V

### Note:

<sup>1.</sup> The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

<sup>2.</sup>The data tested by pulsed , pulse width  $\leqq$  300us , duty cycle  $\leqq$  2%

<sup>3.</sup> The EAS data shows Max. rating . The test condition is  $V_{DD}$ =25V, $V_{GS}$ =10V,L=0.1mH, $I_{AS}$ =12.7A

<sup>4.</sup> The power dissipation is limited by 150°C junction temperature

<sup>5.</sup> The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.



# P-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

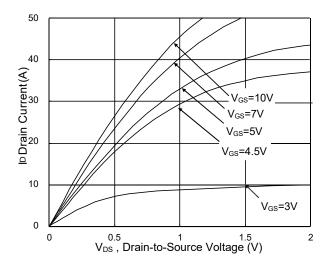
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-30			V
△BV <sub>DSS</sub> /△T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =-1mA		-0.021		V/°C
В	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-8A		25	30	m0
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-6A		30	35	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> . I <sub>D</sub> =-250uA	-1.0		-2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	VGS-VDS , ID250UA		-4.2		mV/°C
	Dunin Course London Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	· uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-8A		12.6		S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		15		Ω
Qg	Total Gate Charge (-4.5V)			9.8		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =-20V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-6A		2.2		nC
Q <sub>gd</sub>	Gate-Drain Charge			3.4		
T <sub>d(on)</sub>	Turn-On Delay Time			16.4		
Tr	Rise Time	$V_{DD}$ =-24V , $V_{GS}$ =-10V , $R_{G}$ =3.3 $\Omega$ ,		20.2		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =-1A		55		ns
T <sub>f</sub>	Fall Time			10		
C <sub>iss</sub>	Input Capacitance			930		
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1MHz		148		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			115		
Is	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-14	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,5</sup>	vg-vp-ov , i orde Gurrent			-24	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	$V_{GS}$ =0V , $I_{S}$ =-1A , $T_{J}$ =25 $^{\circ}$ C			-1.2	V

#### Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper. 2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- 3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =-25V,  $V_{GS}$ =-10V,L=0.1mH,I<sub>AS</sub>=-30A
- 4.The power dissipation is limited by 150°C junction temperature
- 5. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications , should be limited by total power dissipation.



# **N-Channel Typical Characteristics**



**Fig.1 Typical Output Characteristics** 

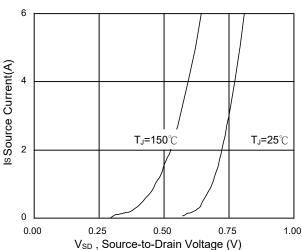


Fig.3 Forward Characteristics Of Reverse

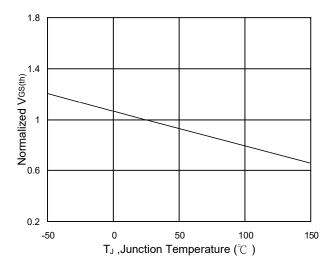


Fig.5 Normalized V<sub>GS(th)</sub> vs. T<sub>J</sub>

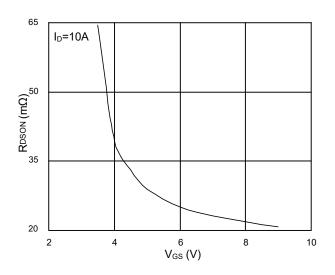


Fig.2 On-Resistance vs. Gate-Source

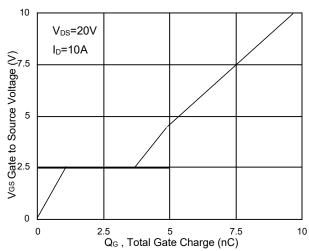


Fig.4 Gate-Charge Characteristics

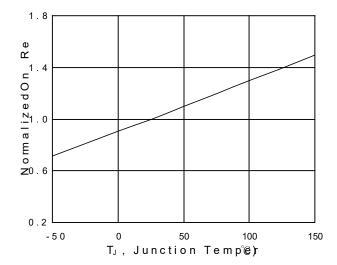
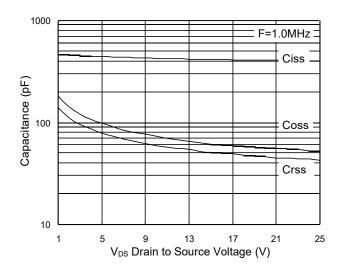


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>





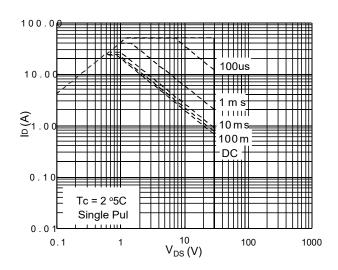


Fig.7 Capacitance

Fig.8 Safe Operating Area

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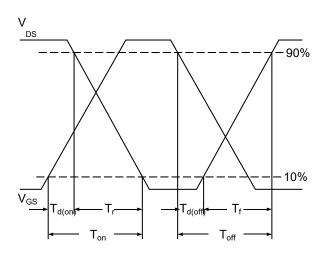
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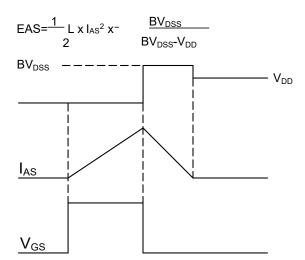
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Fig.9 Normalized Maximum Transient Thermal Impedance

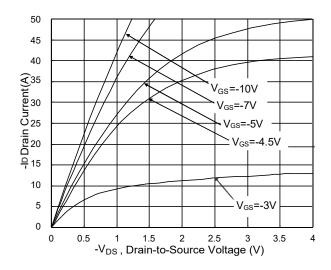
t, Pulse Width (s)







# **P-Channel Typical Characteristics**



**Fig.1 Typical Output Characteristics** 

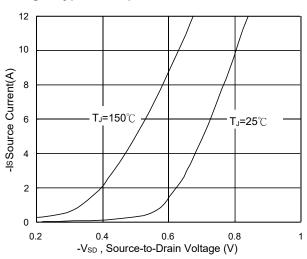


Fig.3 Forward Characteristics Of Reverse

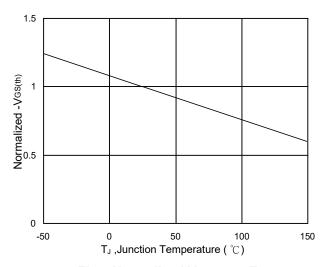


Fig.5 Normalized  $V_{\text{GS(th)}}$  v.s  $T_{\text{J}}$ 

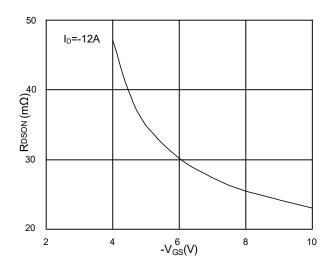


Fig.2 On-Resistance v.s Gate-Source

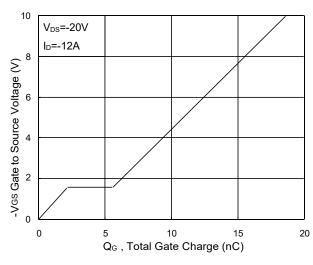


Fig.4 Gate-Charge Characteristics

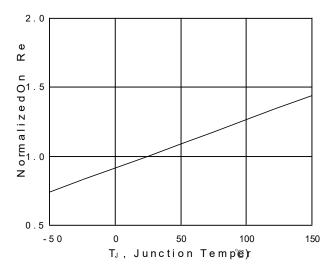
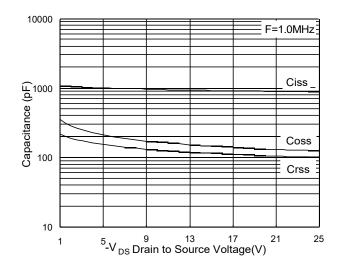


Fig.6 Normalized R<sub>DSON</sub> v.s T<sub>J</sub>





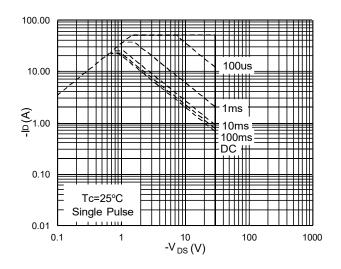


Fig.7 Capacitance

Fig.8 Safe Operating Area

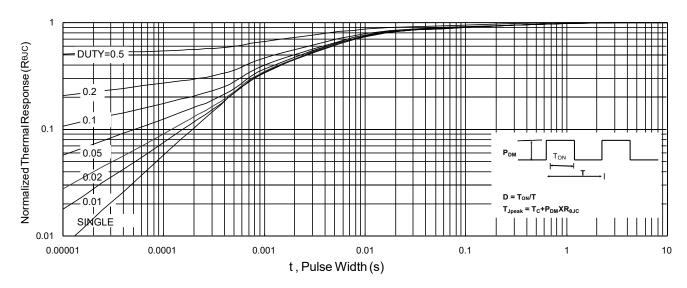


Fig.9 Normalized Maximum Transient Thermal Impedance

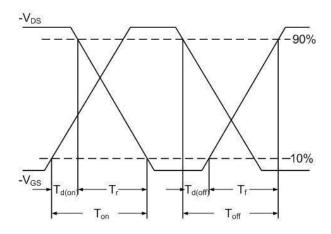


Fig.10 Switching Time Waveform

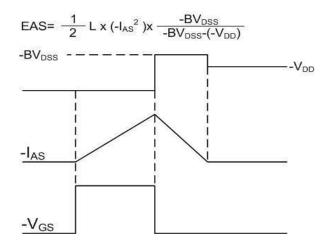
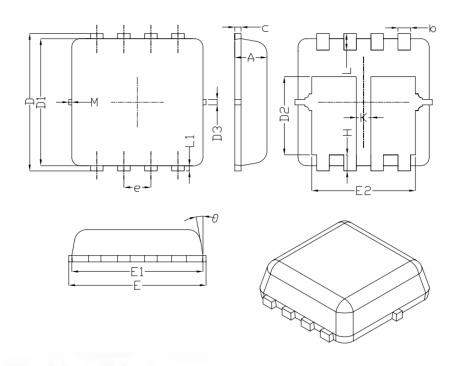


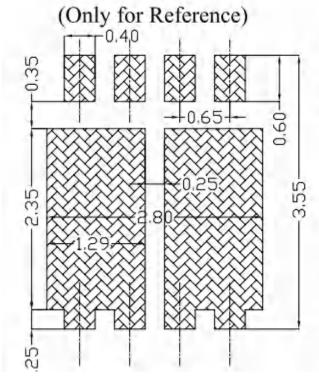
Fig.11 Unclamped Inductive Switching Waveform



# **DFN3X3-8L Package Information**



# Land Pattern



SYMBOL	DIMENSIONAL REOMTS			
	MIN	NOM	MAX	
A	0.70	0.75	0.80	
b	0.25	0.30	0.35	
C	0.10	0.15	0.25	
D	3.25	3.35	3.45	
D1	3.00	3.10	3.20	
D2	1.78	1.88	1.98	
D3	***	0.13	777	
E	3.20	3.30	3.40	
E1	3.00	3.15	3.20	
E2	2.39	2.49	2.59	
e	0.65BSC			
Н	0.30	0.39	0.50	
L	0.30	0.40	0.50	
Ll		0.13		
K	0.30		-	
θ	4	10°	12°	
M	. We	*	0.15	
* No	specified			

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